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**PATENT NUMBER and
ISSUE DATE**

U.S. UTILITY Patent Application

APPL. NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10082658	10/19/2001	378	119	2882	Thomas, C

APPLICANTS: Richardson Martin;

****CONTINUING DATA VERIFIED:**

THIS APPLICATION IS A CIP OF 09/881,620 06/14/2001

AND CLAIMS BENEFIT OF 60/242,102 10/20/2000

verified *CT*

**** FOREIGN APPLICATIONS VERIFIED:**

none *CT*

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed

☐ yes ☒ no

35 USC 119 conditions met

☐ yes ☒ no

Verified and Acknowledged Examiners's initials

ATTORNEY DOCKET NO

UCIF-306CIP

TITLE : EUV, XUV, and X-ray wavelength sources created from laser plasma produced from liquid metal solutions, and nano-size particles in solutions

U.S. DEPT. OF COMM. PAT. & TM. PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED

7/02/03

ISSUE FEE

Amount Due

Date Paid

\$950



TERMINAL

DISCLAIMER

Courtney Thomas
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PRIMARY EXAMINER

David V. Bruce
Primary Examiner
PREPARED FOR ISSUE

CLAIMS
Total Claims 28
Print Claims for 03 1

DRAWING
Sheets Drawn 6
Figs. Drawn 8
Print Figs 24

Allen Quinn
Application Examiner 7/02/03

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